

FORM PTO-1449  
US Department of Commerce  
Patent and Trademark Office



INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT  
(Use Several Sheets if Necessary)

Docket Number  
8571:78CIP

Serial Number  
10/152,743

10/152,743


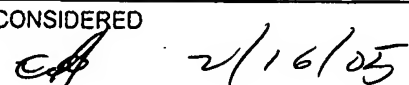
Filing Date  
5/22/02

Group Art Unit  
Not yet assigned 2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	X	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
dl	A1	4,553,238	11/12/85	Shaw <i>et al.</i>	372	6	09/30/83
	A2	4,713,822	12/15/87	Lee	372	69	05/24/85
	A3	5,048,026	09/10/91	Shaw <i>et al.</i>	372	6	05/04/88
	A4	5,086,433	02/04/92	Pochelle <i>et al.</i>	372	72	06/12/90
	A5	5,172,388	12/15/92	Long <i>et al.</i>	372	70	07/23/91
	A6	5,271,031	12/14/93	Baer	372	93	06/02/89
	A7	5,285,467	02/08/94	Scheps	372	69	02/22/93
	A8	5,335,236	08/02/94	Toeppen	372	25	06/03/93
	A9	5,608,166	03/04/97	Monchalin <i>et al.</i>	73	657	10/12/95
	A10	5,790,303	08/04/98	Weston, <i>et al.</i>	359	345	01/23/97
	A11	5,872,804	02/16/99	Kan <i>et al.</i>	372	93	07/17/97
	A12	5,991,315	11/23/99	Injeyan <i>et al.</i>	372	11	09/03/98
	A13	5,930,282	07/27/99	Unternahrer <i>et al.</i>	372	69	05/19/97
	A14	6,094,447	07/25/00	Drake, Jr.	372	75	06/12/98
	A15	6,134,258	10/17/00	Tulloch <i>et al.</i>	372	99	03/25/98
	A16	6,157,663	12/05/00	Wu <i>et al.</i>	372	75	04/16/98
	A17	6,167,181	12/26/00	Fukaishi	385	123	01/04/99
	A18	6,285,704 B1	09/04/01	Kullander-Sjoberg <i>et al.</i>	372	96	07/13/98

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLAS S	TRANSLATION	
							YES	NO
dl	B1	EP 0136871 A2	11/12/85	Europe				X
	B2	EP 0403382 A2	05/07/85	Europe				X
	B3	EP 0657070 A1	12/08/94	Europe				X
	B4	EP 0821453 A2	07/18/97	Europe				X
	B5							X
	B6							X
	B7							X
								X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
24	C1	<del>International Search Report, PCT</del>
↑	C2	C. Honninger, et al.; <i>Diode-Pumped Thin-Disk Yb: YAG Regenerative Amplifier</i> ; APPLIED PHYSICS B, pp. 423-426
↓	C3	Steven Jackel, et al.; <i>High-Energy Nd:Dr:GSGG Lasers Based on Phase and Polarization Conjugated Multiple-Pass Amplifiers</i> ; OPTICAL ENGINEERING, Vol. 36, No. 7, July 1997, pp. 2031-2036
↓	C4	K. F. Wall, et al.; <i>A Ti:Al<sub>2</sub>O<sub>3</sub> Master-Oscillator/Power-Amplifier System</i> ; IEEE JOURNAL OF QUANTUM ELECTRONICS, June 1993, No. 6, pp. 1505-1514
EXAMINER		DATE CONSIDERED
		




Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213002	Application No. 10/806496
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Peter J. de Groot et al.	
		Filing Date March 22, 2004	Group Art Unit 2877

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
dy	AA	4,743,117	05/1988	Kitabayashi et al.	356	520	
	AB	2003/0043385	03/2003	Kuchel, Michael	356	513	
	AC	2003/0011783	01/2003	Suzuki et al.	356	512	
	AD	5,485,275	01/1996	Ohtsuka, Masaru	356	513	
	AE	4,898,470	02/1990	Cleaveland, Edwin E.	356	513	
	AF	4,387,994	06/1983	Balasubramanian, N.	356	513	
	AG	2001/0028462	10/2001	Ichihara et al.	356	512	
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	


Examiner Signature 	Date Considered 2/16/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. <del>10/190,353</del> 10/806,496
	Applicant Peter de Groot et al.		Group Art Unit 2877
	Filing Date July 3, 2002		

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
sk	AA	6,195,168	2/27/2001	De Lega et al.	356	497	
	AB	6,154,279	11/28/2000	Thayer	356	376	
	AC	5,991,035	11/23/1999	Bruning	356	359	
	AD	5,784,164	7/21/1998	Deck et al.	356	359	
	AE	5,398,113	3/14/1995	de Groot	356	360	
	AF	4,872,755	10/10/1989	Küchel	356	360	
	AG	4,340,306	7/20/1982	Balasubramanian	356	360	
	AH						
	AI						

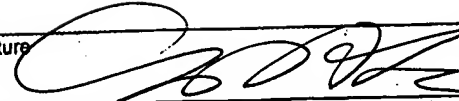
Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
sk	AJ	WO 02/14845	2/21/2002	WIPO	G01N	21/954		
	AK	WO 01/75395	10/11/2001	WIPO	G01B	11/30		
	AL	WO 01/27558	4/19/2001	WIPO	G01B	11/30		
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	AN							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
sk	AO	Boppart et al., "Forward-imaging instruments for optical coherence tomography", <u>Optics Letters</u> , Vol. 22, No. 21, pp. 1618-1620 (November 1, 1997)
	AP	Blümel et al., "Absolute interferometric calibration of toric and conical surfaces", <u>SPIE</u> , Vol. 3134, pp. 370-378 (July 1997)
	AQ	Brinkman et al., "Testing of rod objects by grazing-incidence interferometry: experiment", <u>Applied Optics</u> , Vol. 38, No. 1, pp. 121-125 (January 1, 1999)
	AR	Chakmakjian et al., "Simultaneous focus and coherence scanning in interference microscopy", <u>Technical Digest, International Workshop on Interferometry</u> , 171 (Riken, Japan, 1996)
	AS	Dresel et al., "Three-dimensional sensing of rough surfaces by coherence radar", <u>Applied Optics</u> , Vol. 31, No. 7, pp. 919-925 (March 1, 1992)
	AT	Li et al., "Imaging needle for optical coherence tomography", <u>Optics Letters</u> , Vol. 25, No. 20, pp. 1520-1522 (October 15, 2000)

Examiner Signature 	Date Considered 2/16/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant Peter de Groot et al.	
(37 CFR §1.98(b))		Filing Date July 3, 2002	Group Art Unit 2877

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
all	BA	Lindner et al., "White-light interferometry via an endoscope", <u>SPIE</u> , Vol. 4777, pp. 90-101 (July 2002)
✓	BB	Matthys et al., "Panoramic Holoferometry", <u>Experimental Mechanics</u> , Vol. 35, No. 1, pp. 83-88 (March 1995)
✓	BC	Schwider, "White-light Fizeau interferometer", <u>Applied Optics</u> , Vol. 36, No. 7, pp. 1433-1437 (March 1, 1997)
✓	BD	Zhou et al., "Surface profile measurements using a white light Linnik interferometer", <u>Annual Report Lehrstuhl für Optik, Univ. Erlangen-Nürnberg</u> pp. 69 (1996)
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	BF	


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Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>09712-213001</b>	Application No. <b>10/190,353</b>
	Applicant <b>Peter de Groot et al.</b>		
	Filing Date <b>July 3, 2002</b>	Group Art Unit <b>2877</b>	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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<i>AL</i>	AB	4,725,144	2/16/1988	Nelson et al.	356	360	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
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	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
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